Measurement:	PL	
System:	Renishaw inVia Raman spectrometer	
Additional setup:	Custom-made sample stage with an integrated Peltier element	
Measurement geometry:	Backscattering - incident beam linearly polarized - scattered light not restricted in terms of polarization	
Objective:	Nikon LD 50x/0.45	
Grating:	1800 l/mm	
Nominal resolution:	1.5 cm^{-1}	
Slit width:	65 µm	
Collection mode:	extstep:	Stepwise movement of the grating to expand the full measurement range. The full PL spectra are assembled out of CCD frames obtained at the different grating positions (spectral overlap: 10 pixels).
Additional information:	All spectra are response corrected (RC)	
File labeling:	*Sample name _ measurement _ layer – measurement number _ laser wavelength _ collection mode _ exposure time _ laser power _ temperature*.txt	